PROBING NIFE NANOSCALE ALLOY FILMS WITH PHOTOEMISSION MAGNETIC X-RAY LINEAR DICHROISM; AG.J. Mankey, AR.F. Willis, BJ.G. Tobin, BK.W. Goodman, CJ.D. Denlinger, CE. Rotenberg, and CA.Warwick; APennyslvania State University, Physics Department, College Station, PA 16802, BLawrence Livermore National Laboratory, Livermore, CA 94550, CAdvanced Light Source, Lawrence Berkeley Laboratory, Berkeley, CA 94720

The magnetic structure of NiFe nanoscale alloy films (thickness of about 1 nm) has been nvestigated as a function of composition, with full elemental specificity. To do this, we have used the magnetic x-ray linear dichroism (MXLD) in angle-resolved photoemission. FeNi films were grown using MBE techniques<sup>1</sup> upon the surface of Cu(001). The MXLD measurements were made at the Advanced Light Source. While our MXLD work has been based upon the groundbreaking measurements of Roth et al.<sup>3</sup> and subsequent investigations<sup>4,5</sup>, our extension to nanoscale alloy films permits a full utilization of a key component of these x-ray based echniques: elemental specificity. The MXLD results will be directly compared to predictions of a theoretical model<sup>6</sup>. Crucial issues such as the invar effect will be addressed<sup>7</sup>.

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